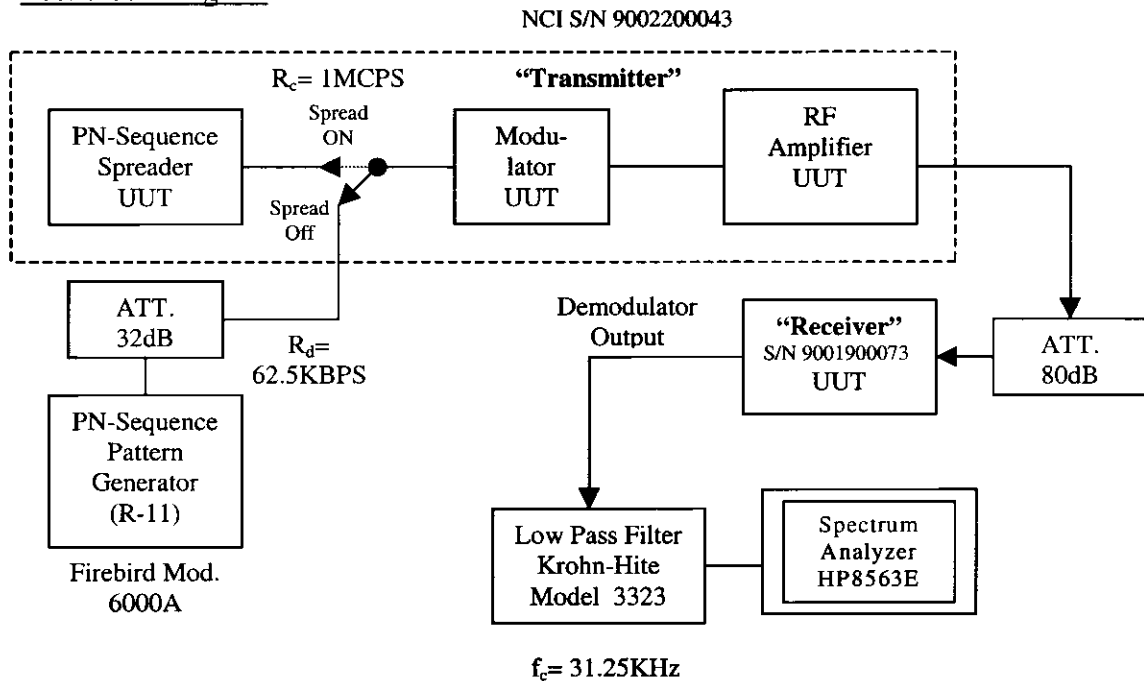


## “Processing Gain Measurement”

Reference: FCC Requirements Part 15, Paragraph 15.247, (e), (1)

Test block diagram:



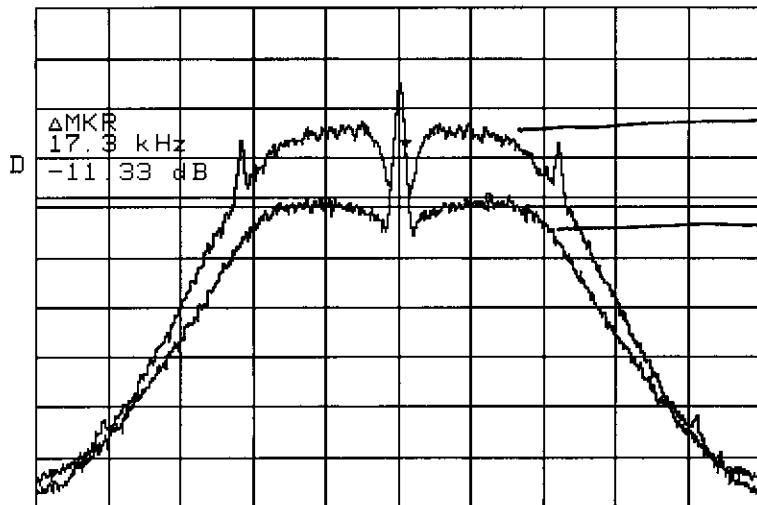
Test Parameters:

- 1) Data rate  $R_d = 62.5\text{KBPS}$   
Symbol rate  $R_s = 31.25\text{KSPS}$
- 2) Chip Rate  $R_c = 1\text{MCPS}$
- 3) Processing gain  $G_p = 10 * \text{Log}(R_c/R_d) = 12\text{dB}$
- 4) Receiver lowpass filter cut-off frequency  
 $f_c = \text{symbol rate} = 31.25\text{KHz}$
- 5) Lowpass filter characteristic: Maximally flat, 48dB/Octave

Test method (para. 15.247 (e) (1)):

- 1) The data sequence is generated by the PN-Sequence pattern generator at 62.5KHz. This generator emulates the original data generated internally by the ASIC chip in the UUT. The test pattern used is a maximal sequence of length 2047 (R-11).
- 2) The processing gain is the difference between the unspread S/N to the spread S/N at the output of the lowpass filter, expressed in "dB".
- 3) Since the noise power at the output of the lowpass filter does not change when the signal is unspread or spread, the processing gain is measured by comparing the power spectrum of the unspread and spread signals.

ATTEN 30dB    VAVG 100    ΔMKR -11.33dB  
RL 20.0dBm    10dB/    17.3kHz



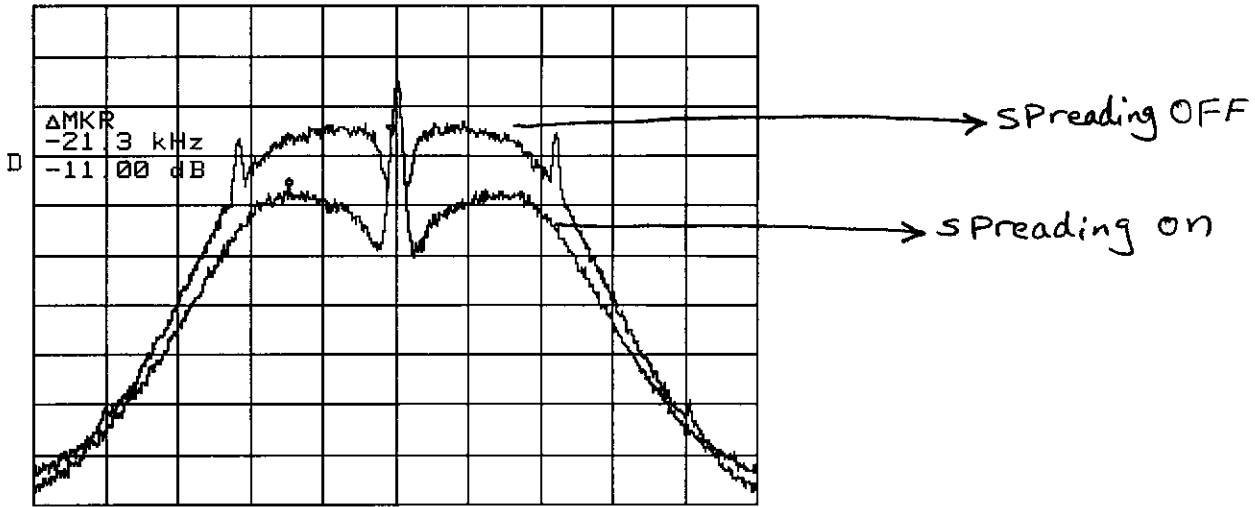
→ SPreading OFF

→ SPreading ON

CENTER 0Hz    SPAN 150.0kHz  
RBW 1.0kHz    VBW 1.0kHz    SWP 380ms

Processing Gain > 11.33 dB @ chan  $\phi$

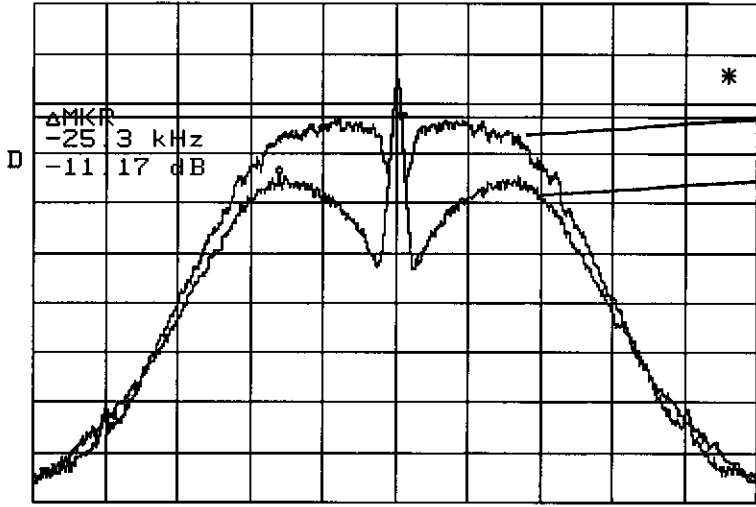
ATTEN 30dB VAUG 100 ΔMKR -11.00dB  
RL 20.0dBm 10dB/ -21.3kHz



CENTER 0Hz SPAN 150.0kHz  
RBW 1.0kHz VBW 1.0kHz SWP 300ms

Processing Gain > 11.0 dB @ ch 8

ATTEN 30dB    VAVG 100    ΔMKR -11.17dB  
RL 20.0dBm    10dB/    -25.3kHz



CENTER 0Hz    SPAN 150.0kHz  
RBW 1.0kHz    VBW 1.0kHz    SWP 380ms

Processing Gain > 11.17 dB @ ch 16